## EH3745TS-5.000M

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## ELECTRICAL SPECIFICATIONS

| Nominal Frequency | 5.000 MHz |
| :--- | :--- |
| Frequency Tolerance/Stability | $\pm 50 \mathrm{ppm}$ Maximum (Inclusive of all conditions: Calibration Tolerance at 25 <br>  <br> Operating Temperature Frequange, Supply Voltage Change, Output Load Change, First Year Agiing at $25^{\circ}$, <br> $260^{\circ} \mathrm{C}$ Reflow, Shock, and Vibration) |
| Aging at 25 ${ }^{\circ} \mathrm{C}$ | $\pm 5 \mathrm{ppm} /$ Year Maximum |
| Operating Temperature Range | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ |
| Supply Voltage | $2.5 \mathrm{Vdc} \pm 5 \%$ |
| Input Current | 6 mA Maximum (No Load) |
| Output Voltage Logic High (Voh) | $90 \%$ of Vdd Minimum (IOH $=-8 \mathrm{~mA})$ |
| Output Voltage Logic Low (Vol) | $10 \%$ of Vdd Maximum (IOL $=+8 \mathrm{~mA})$ |
| Rise/Fall Time | 6 nSec Maximum (Measured at 20\% to 80\% of waveform) |
| Duty Cycle | $50 \pm 10(\%)$ (Measured at $50 \%$ of waveform) |
| Load Drive Capability | 15 pF Maximum |
| Output Logic Type | CMOS |
| Pin 1 Connection | Tri-State (High Impedance) |
| Tri-State Input Voltage (Vih and Vil) | $90 \%$ of Vdd Minimum or No Connect to Enable Output, 10\% of Vdd Maximum to Disable Output (High <br> Impedance) |
| Standby Current | $10 \mu \mathrm{~A} \mathrm{Maximum} \mathrm{(Pin} \mathrm{1} \mathrm{=} \mathrm{Ground)}$ |
| Absolute Clock Jitter | $\pm 100 \mathrm{pSec}$ Maximum |
| Start Up Time | 10 mSec Maximum |
| Storage Temperature Range | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |

ENVIRONMENTAL \& MECHANICAL SPECIFICATIONS

| ESD Susceptibility | MIL-STD-883, Method 3015, Class 1, HBM: 1500V |
| :--- | :--- |
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A |
| Flammability | UL94-V0 |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C |
| Mechanical Shock | MIL-STD-883, Method 2002, Condition B |
| Moisture Resistance | MIL-STD-883, Method 1004 |
| Moisture Sensitivity | J-STD-020, MSL 1 |
| Resistance to Soldering Heat | MIL-STD-202, Method 210, Condition K |
| Resistance to Solvents | MIL-STD-202, Method 215 |
| Solderability | MIL-STD-883, Method 2003 |
| Temperature Cycling | MIL-STD-883, Method 1010, Condition B |
| Vibration | MIL-STD-883, Method 2007, Condition A |

## EH3745TS-5.000M

## MECHANICAL DIMENSIONS (all dimensions in millimeters)



## Suggested Solder Pad Layout

All Dimensions in Millimeters


All Tolerances are $\pm 0.1$

## OUTPUT WAVEFORM \& TIMING DIAGRAM



## Test Circuit for CMOS Output



Note 1: An external $0.01 \mu \mathrm{~F}$ ceramic bypass capacitor in parallel with a $0.1 \mu \mathrm{~F}$ high frequency ceramic bypass capacitor close (less than 2 mm ) to the package ground and supply voltage pin is required.
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth ( $>300 \mathrm{MHz}$ ) passive probe is recommended.
Note 3: Capacitance value $\mathrm{C}_{\mathrm{L}}$ includes sum of all probe and fixture capacitance.

## EH3745TS-5.000M

## Recommended Solder Reflow Methods



High Temperature Infrared/Convection

| $\mathrm{T}_{\mathrm{S}}$ MAX to $\mathrm{T}_{\mathrm{L}}$ (Ramp-up Rate) | $3^{\circ} \mathrm{C} /$ second Maximum |
| :---: | :---: |
| Preheat |  |
| - Temperature Minimum ( $\mathrm{T}_{\mathrm{s}} \mathrm{MIN}$ ) | $150^{\circ} \mathrm{C}$ |
| - Temperature Typical ( $\mathrm{T}_{\mathrm{s}}$ TYP) | $175{ }^{\circ} \mathrm{C}$ |
| - Temperature Maximum (TS MAX) | $200^{\circ} \mathrm{C}$ |
| - Time ( $\mathrm{ts}_{\text {s MIN} \text { ) }}$ | 60-180 Seconds |
| Ramp-up Rate ( $\mathrm{T}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{P}}$ ) | $3^{\circ} \mathrm{C} /$ second Maximum |
| Time Maintained Above: |  |
| - Temperature ( $\mathrm{T}_{\mathrm{L}}$ ) | $217{ }^{\circ} \mathrm{C}$ |
| - Time ( $t_{\text {L }}$ ) | 60-150 Seconds |
| Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ ) | $260^{\circ} \mathrm{C}$ Maximum for 10 Seconds Maximum |
| Target Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ Target) | $250^{\circ} \mathrm{C}+0 /-5^{\circ} \mathrm{C}$ |
| Time within $5^{\circ} \mathrm{C}$ of actual peak ( $\mathrm{t}_{\mathrm{p}}$ ) | 20-40 seconds |
| Ramp-down Rate | $6^{\circ} \mathrm{C} /$ second Maximum |
| Time $25^{\circ} \mathrm{C}$ to Peak Temperature (t) | 8 minutes Maximum |
| Moisture Sensitivity Level | Level 1 |

## EH3745TS-5.000M

## Recommended Solder Reflow Methods



Low Temperature Infrared/Convection $240^{\circ} \mathrm{C}$

| $\mathrm{T}_{\mathrm{S}}$ MAX to $\mathrm{T}_{\mathrm{L}}$ (Ramp-up Rate) | $5^{\circ} \mathrm{C} /$ second Maximum |
| :---: | :---: |
| Preheat |  |
| - Temperature Minimum ( $\mathrm{T}_{\mathrm{s}} \mathrm{MIN}$ ) | N/A |
| - Temperature Typical (Ts TYP) | $150^{\circ} \mathrm{C}$ |
| - Temperature Maximum (Ts MAX) | N/A |
| - Time (ts MIN) | 60-120 Seconds |
| Ramp-up Rate ( $\mathrm{L}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{P}}$ ) | $5^{\circ} \mathrm{C} /$ second Maximum |
| Time Maintained Above: |  |
| - Temperature ( $\mathrm{T}_{\mathrm{L}}$ ) | $150^{\circ} \mathrm{C}$ |
| - Time ( $\mathrm{t}_{\mathrm{L}}$ ) | 200 Seconds Maximum |
| Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ ) | $240^{\circ} \mathrm{C}$ Maximum |
| Target Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ Target) | $240^{\circ} \mathrm{C}$ Maximum 1 Time / $230^{\circ} \mathrm{C}$ Maximum 2 Times |
| Time within $5^{\circ} \mathrm{C}$ of actual peak ( $\mathrm{t}_{\mathrm{p}}$ ) | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate | $5^{\circ} \mathrm{C} /$ second Maximum |
| Time $25^{\circ} \mathrm{C}$ to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |

## Low Temperature Manual Soldering

$185^{\circ} \mathrm{C}$ Maximum for 10 seconds Maximum, 2 times Maximum.
High Temperature Manual Soldering
$260^{\circ} \mathrm{C}$ Maximum for 5 seconds Maximum, 2 times Maximum.

